

# TPIC2701

## 7-CHANNEL COMMON-SOURCE POWER DMOS ARRAY

SLIS019A – SEPTEMBER 1992 – REVISED SEPTEMBER 1996

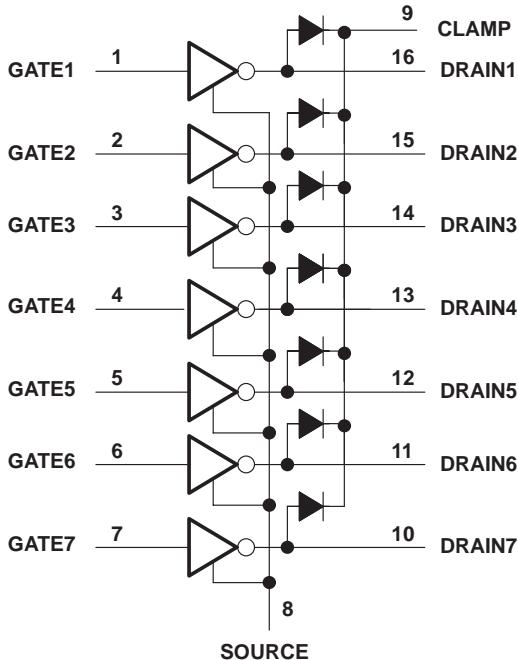
- Seven 0.5-A Independent Output Channels
- Integrated Clamp Diode With Each Output
- Low  $r_{DS(on)}$  . . . 0.5 Ω Typical
- Output Voltage . . . 60 V
- Pulsed Current . . . 3 A Per Channel
- Avalanche Energy . . . 22 mJ

### description

The TPIC2701 is a monolithic power DMOS transistor array that consists of seven independent N-channel enhancement-mode DMOS transistors connected in a common-source configuration with open drains. The TPIC2701 is pin-for-pin functionally compatible with the Texas Instruments ULN2001A through ULN2004A.

The TPIC2701 is characterized for operation over a temperature range of 0°C to 125°C. The TPIC2701M is characterized for operation over the full military temperature range of -55°C to 125°C.

### logic diagram



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

**TPIC2701  
N PACKAGE  
(TOP VIEW)**

GATE1	1	16	DRAIN1
GATE2	2	15	DRAIN2
GATE3	3	14	DRAIN3
GATE4	4	13	DRAIN4
GATE5	5	12	DRAIN5
GATE6	6	11	DRAIN6
GATE7	7	10	DRAIN7
SOURCE	8	9	CLAMP

**TPIC2701M  
J PACKAGE†  
(TOP VIEW)**

GATE1	1	24	DRAIN1
GATE2	2	23	DRAIN2
GATE3	3	22	DRAIN3
NC	4	21	NC
NC	5	20	NC
GATE4	6	19	DRAIN4
GATE5	7	18	DRAIN5
NC	8	17	NC
GATE6	9	16	DRAIN6
GATE7	10	15	DRAIN7
SOURCE	11	14	CLAMP
SOURCE	12	13	SOURCE

NC – No internal connection

† Refer to the mechanical data for the JW package.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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### absolute maximum ratings over operating case temperature range (unless otherwise noted)

Drain-source voltage, $V_{DS}$	.....	60 V
Gate-source voltage, $V_{GS}$	.....	$\pm 20$ V
Clamp-drain voltage, $V_{CD}$	.....	60 V
Continuous source-drain diode current	.....	0.5 A
Pulsed drain current, each output, $I_D$ (see Note 1 and Figure 17)	.....	3 A
Pulsed clamp current, $I_{CL}$ (see Note 1 and Figure 18)	.....	3 A
Continuous drain current, each output, all outputs on	.....	0.5 A
Single-pulse avalanche energy, $E_{AS}$ (see Figure 4)	.....	22 mJ
Continuous total power dissipation	.....	See Dissipation Rating Table
Operating virtual junction temperature range, $T_J$ : TPIC2701	.....	-40°C to 150°C
TPIC2701M	.....	-55°C to 150°C
Operating case temperature range, $T_C$ : TPIC2701	.....	-40°C to 125°C
TPIC2701M	.....	-55°C to 125°C
Storage temperature range, $T_{Stg}$	.....	-65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds: N Package	.....	260°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds: J Package	.....	300°C

NOTE 1: Pulse duration = 10 ms, duty cycle = 6%.

DISSIPATION RATING TABLE

PACKAGE	$T_A \leq 25^\circ\text{C}$ POWER RATING	DERATING FACTOR ABOVE $T_A = 25^\circ\text{C}$	$T_A = 70^\circ\text{C}$ POWER RATING	$T_A = 85^\circ\text{C}$ POWER RATING	$T_A = 125^\circ\text{C}$ POWER RATING
J	2660 mW	21.3 mW/°C	1701 mW	1382 mW	530 mW
N	1400 mW	11.0 mW/°C	905 mW	740 mW	300 mW

### electrical characteristics, $T_C = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS	TPIC2701			UNIT
		MIN	TYP	MAX	
$V_{(BR)DS}$ Drain-source breakdown voltage	$I_D = 1 \mu\text{A}, V_{GS} = 0$	60			V
$V_{TGS}$ Gate-source threshold voltage	$I_D = 1 \text{ mA}, V_{DS} = V_{GS}$	1.2	1.75	2.4	V
$V_{DS(on)}$ Drain-source on-state voltage	$I_D = 0.5 \text{ A}, V_{GS} = 15 \text{ V},$ See Notes 2 and 3		0.25	0.4	V
$I_{DSS}$ Zero-gate-voltage drain current	$V_{DS} = 48 \text{ V}, V_{GS} = 0$	$T_C = 25^\circ\text{C}$	0.05	1	$\mu\text{A}$
			0.5	10	
$I_{GSSF}$ Forward gate current, drain short circuited to source	$V_{GS} = 20 \text{ V}, V_{DS} = 0$		10	100	nA
$I_{GSSR}$ Reverse gate current, drain short circuited to source	$V_{GS} = -20 \text{ V}, V_{DS} = 0$		10	100	nA
$r_{DS(on)}$ Forward drain-source on-state resistance	$V_{GS} = 15 \text{ V}, I_D = 0.5 \text{ A},$ See Notes 2 and 3 and Figures 5 and 6	$T_C = 25^\circ\text{C}$	0.5	0.8	$\Omega$
		$T_C = 125^\circ\text{C}$	0.8	1.3	
$g_{fs}$ Forward transconductance	$V_{DS} = 15 \text{ V}, I_D = 0.5 \text{ A},$ See Notes 2 and 3		0.5	0.8	S
$C_{iss}$ Short-circuit input capacitance, common source	$V_{DS} = 25 \text{ V}, V_{GS} = 0, f = 300 \text{ kHz}$		105		pF
$C_{oss}$ Short-circuit output capacitance, common source			65		
$C_{rss}$ Short-circuit reverse transfer capacitance, common source			15		

NOTES: 2. Technique should limit  $T_J - T_C$  to 10°C maximum.

3. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts with a single output transistor conducting.



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**electrical characteristics over case temperature operating range (unless otherwise noted) (see Note 4)**

PARAMETER	TEST CONDITIONS	$T_C^\dagger$	TPIC2701M			UNIT
			MIN	TYP	MAX	
$V_{(BR)DS}$ Drain-to-source breakdown voltage	$I_D = 1 \mu A, V_{GS} = 0$	25°C	60			V
	$I_D = 1 mA, V_{GS} = 0$	Full range				
$V_{TGS}$ Gate-to-source input threshold voltage	$I_D = 1 mA, V_{DS} = V_{GS}$	Full range	1.2	1.75	2.4	V
$V_{DS(on)}$ Drain-to-source on-state voltage	$I_D = 0.5 A, V_{GS} = 15 V$	25°C	0.25	0.45	0.65	V
		Full range				
$I_{DSS}$ Zero-gate-voltage drain current	$V_{DS} = 48 V, V_{GS} = 0$	25°C	0.05	1	10	$\mu A$
		Full range				
$I_{GSSF}$ Forward gate current, drain short-circuited to source	$V_{GS} = 20 V, V_{DS} = 0$	25°C	10	100	10	$nA$
		Full range				
$I_{GSSR}$ Reverse gate current, drain short-circuited to source	$V_{GS} = -20 V, V_{DS} = 0$	25°C	10	100	10	$\mu A$
		Full range				
$r_{DS(on)}$ Forward drain-source on-state resistance	$V_{GS} = 15 V, I_D = 0.5 A$	25°C	0.5	0.9	1.3	$\Omega$
		Full range				
$g_{fs}$ Forward transconductance	$V_{DS} = 15 V, I_D = 0.5 A$	25°C	0.8		S	
$C_{iss}$ Short-circuit input capacitance, common source	$V_{DS} = 25 V, V_{GS} = 0, f = 300 kHz$	Full range	105			pF
			65			
			15			

† Full range is  $-55^\circ C$  to  $125^\circ C$ .

NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.

**source-drain diode characteristics,  $T_C = 25^\circ C$**

PARAMETER	TEST CONDITIONS	TPIC2701			UNIT
		MIN	TYP	MAX	
$V_{SD}$ Forward On voltage	$I_S = 0.5 A, V_{GS} = 0$		0.9	1.4	V
$t_{rr(SD)}$ Reverse-recovery time	$I_S = 0.5 A, V_{GS} = 0, V_{DS} = 48 V,$ $di/dt = 25 A/\mu s,$		165		ns
$Q_{RR}$ Total source-drain diode charge	See Figure 1		250		nC

**source-to-drain diode characteristics over operating case temperature range (unless otherwise noted) (see Note 4)**

PARAMETER	TEST CONDITIONS	TPIC2701M			UNIT
		MIN	TYP	MAX	
$V_{SD}$ Forward On voltage	$I_S = 0.5 A, V_{GS} = 0$		0.9	1.4	V
$t_{rr}$ Reverse recovery time	$I_S = 0.5 A, V_{GS} = 0, V_{DS} = 48 V,$ $di/dt = 25 A/\mu s,$		165		ns
$Q_{RR}$ Total source-to-drain diode charge	$T_C = 25^\circ C$ , See Figure 1		250		nC

NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.



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### clamp diode characteristics, $T_C = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TPIC2701			UNIT
		MIN	TYP	MAX	
$V_F$	Forward on-voltage	$I_F = 0.5 \text{ A}$		1 1.5	V
$V_{BR}$	Breakdown voltage	$I_R = 1 \mu\text{A}$		60	V
$I_R$	Reverse leakage current	$V_R = 48 \text{ V}$		0.05 1	$\mu\text{A}$
$t_{rr(CD)}$	Reverse-recovery time	$I_F = 0.1 \text{ A}, \frac{dI}{dt} = 25 \text{ A}/\mu\text{s}$		90	ns
$Q_{RR}$	Total source-drain diode charge	$V_{CD} = 48 \text{ V}, \text{ See Figure 1}$		100	nC

### clamp diode characteristics over operating case temperature range (unless otherwise noted) (see Note 4)

PARAMETER	TEST CONDITIONS	TPIC2701M			UNIT
		MIN	TYP	MAX	
$V_F$	Forward voltage	$I_F = 0.5 \text{ A}$		1 1.5	V
$V_{(BR)}$	$I_R = 1 \mu\text{A}, T_C = 25^\circ\text{C}$		60		V
$I_R$	$V_R = 48 \text{ V}$	$T_C = 25^\circ\text{C}$		0.05 1	$\mu\text{A}$
				10	
$t_{rr(SD)}$	Reverse recovery time, source-to-drain	$I_F = 0.1 \text{ A}, \frac{dI}{dt} = 25 \text{ A}/\mu\text{s}, T_C = 25^\circ\text{C}$		90	ns
$Q_{RR}$	Total source-to-drain diode charge	$V_{CD} = 48 \text{ V}, \text{ See Figure 1}$		100	nC

NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.

### resistive-load switching characteristics, $T_C = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TPIC2701			UNIT
		MIN	TYP	MAX	
$t_{d(on)}$	$V_{DD} = 25 \text{ V}, R_L = 100 \Omega, t_{en} = 10 \text{ ns}, t_{dis} = 10 \text{ ns}, \text{ See Figure 2}$		10		ns
$t_{d(off)}$			30		
$t_r$			15		
$t_f$			5		
$Q_g$	$V_{DS} = 48 \text{ V}, I_D = 0.25 \text{ A}, V_{GS} = 10 \text{ V}, \text{ See Figure 3}$		2.8	3.6	nC
$Q_{gs}$			1.6	2	
$Q_{gd}$			1.2	1.6	

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**resistive-load switching characteristics over operating case temperature range (unless otherwise noted) (see Note 4)**

PARAMETER	TEST CONDITIONS	TPIC2701M			UNIT
		MIN	TYP	MAX	
$t_{d(on)}$	$V_{DD} = 25 \text{ V}$ , $R_L = 100 \Omega$ , $t_{en} = 10 \text{ ns}$ , $t_{dis} = 10 \text{ ns}$ , See Figure 2	10			ns
$t_{d(off)}$		30			
$t_r$		15			
$t_f$		5			
$Q_g$	$V_{DS} = 48 \text{ V}$ , $I_D = 0.25 \text{ A}$ , $V_{GS} = 10 \text{ V}$ , See Figure 3	2.8			nC
$Q_{gs}$		1.6			
$Q_{gd}$		1.2			

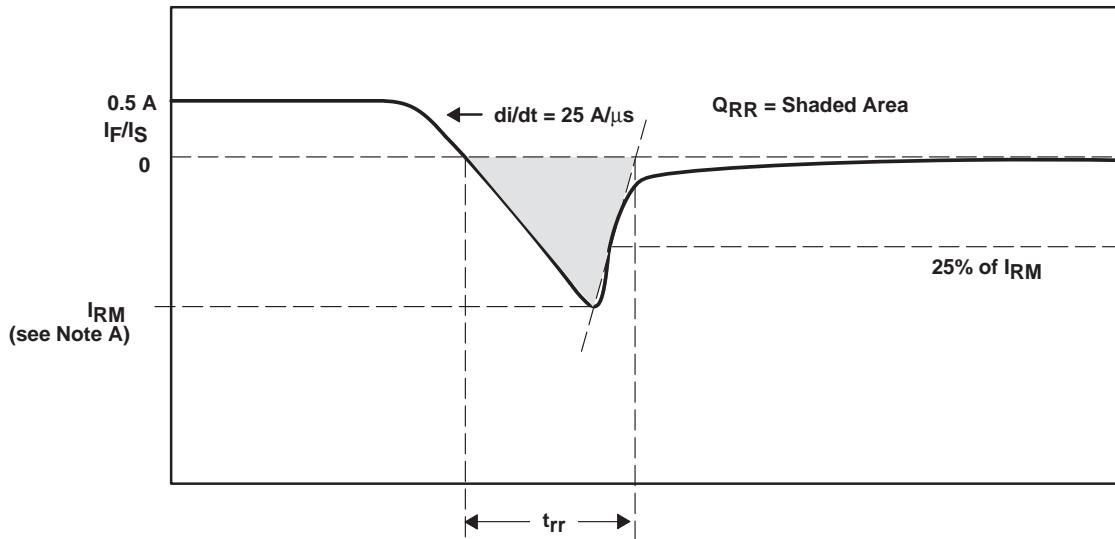
NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.

#### thermal resistance

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$R_{\theta JA}$	N package with all outputs at equal power			90	°C/W
	J package with all outputs at equal power			66	

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#### PARAMETER MEASUREMENT INFORMATION



NOTE A:  $I_{RM}$  = maximum recovery current

**Figure 1. Reverse-Recovery-Current Waveforms of Source-Drain and Clamp Diodes**

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### PARAMETER MEASUREMENT INFORMATION

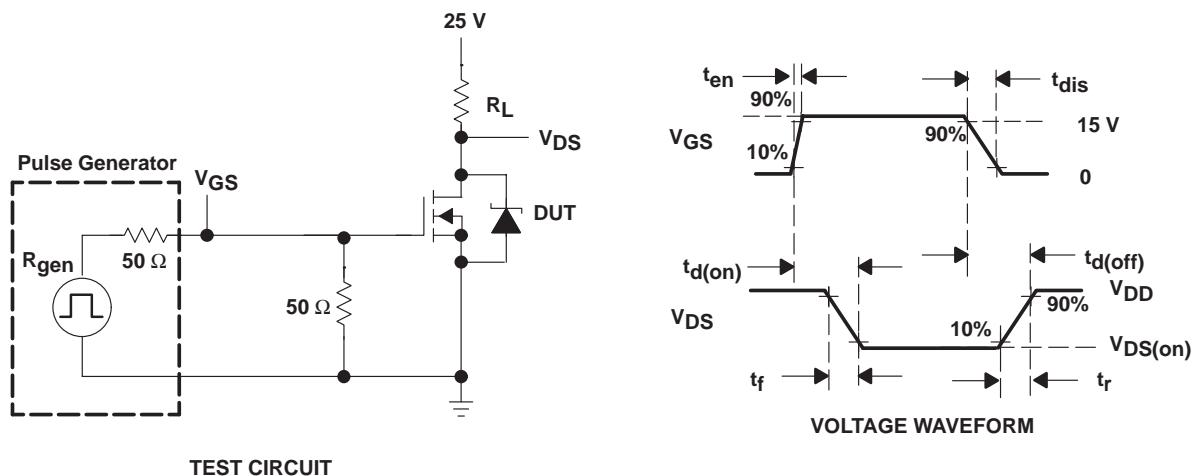


Figure 2. Resistive Switching

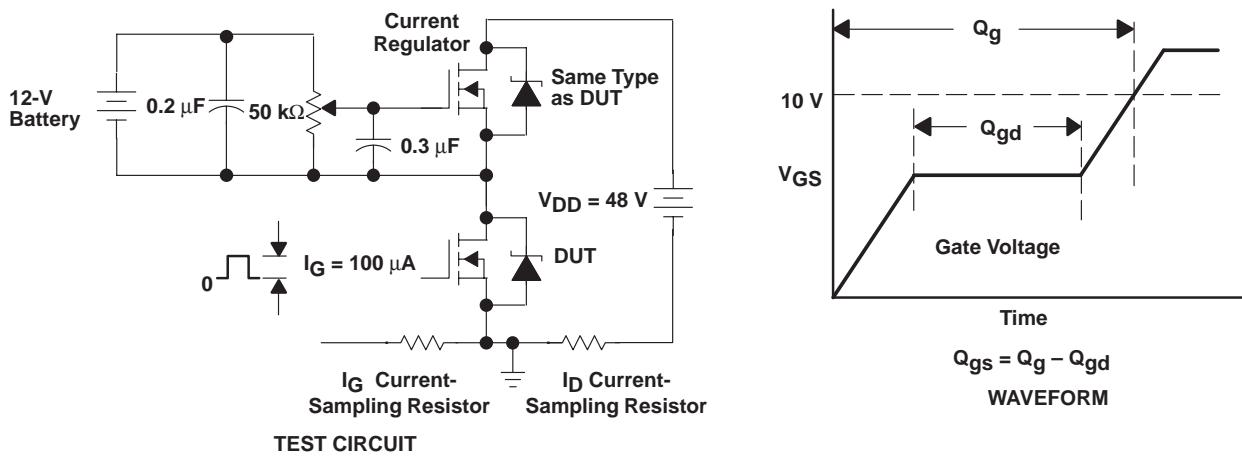
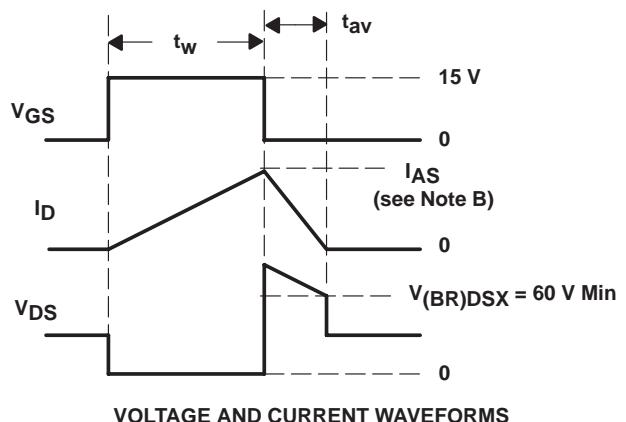
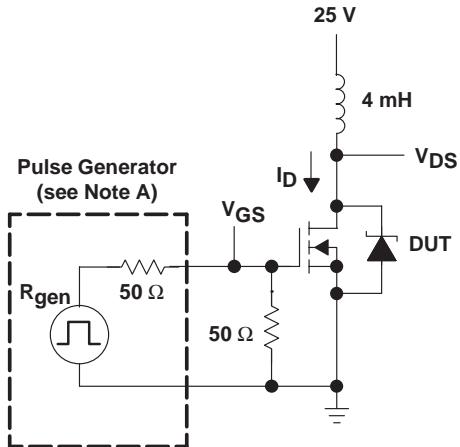


Figure 3. Gate Charge Test Circuit and Waveform

### PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT

NOTES: A. The pulse generator has the following characteristics:  $t_r \leq 10 \text{ ns}$ ,  $t_f \leq 10 \text{ ns}$ ,  $Z_O = 50 \Omega$ .

B. Input pulse duration ( $t_W$ ) is increased until peak current  $I_{AS} = 2.5 \text{ A}$ .

$$\text{Energy test level is defined as } E_{AS} = \frac{I_{AS} \times V_{(BR)DSX} \times t_{av}}{2} = 22 \text{ mJ min.}$$

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms

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### TYPICAL CHARACTERISTICS

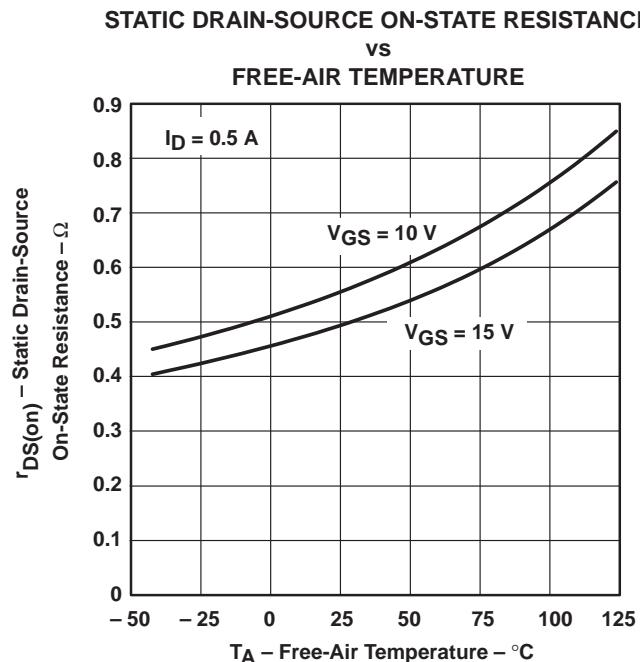


Figure 5

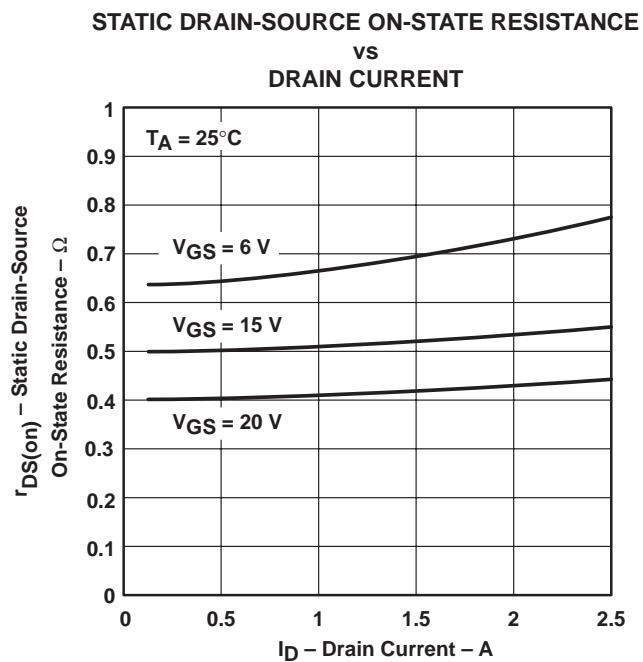


Figure 6

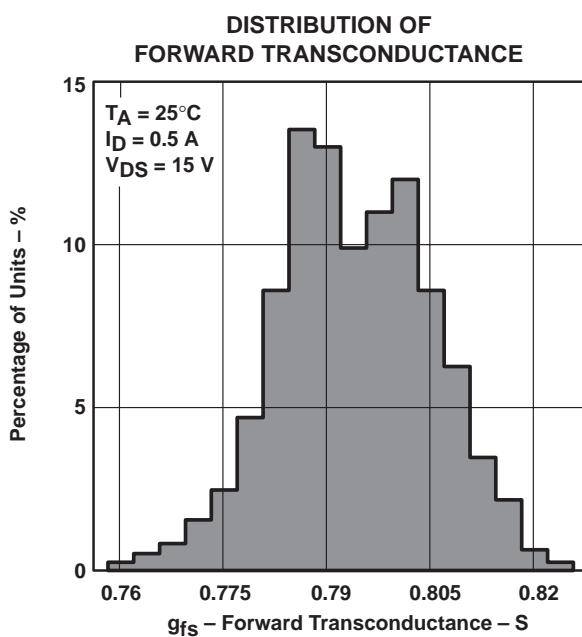


Figure 7

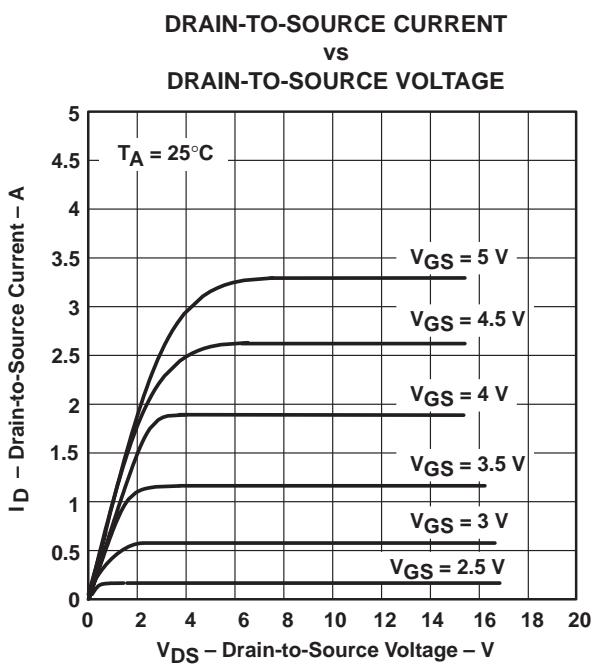


Figure 8

### TYPICAL CHARACTERISTICS

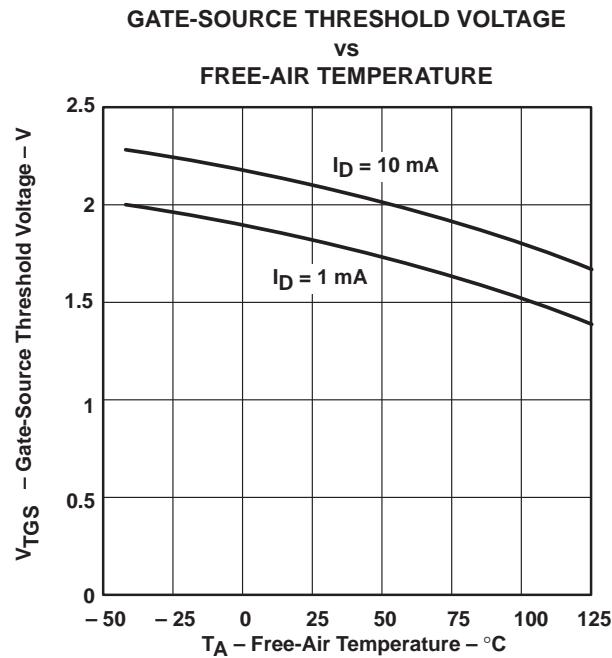


Figure 9

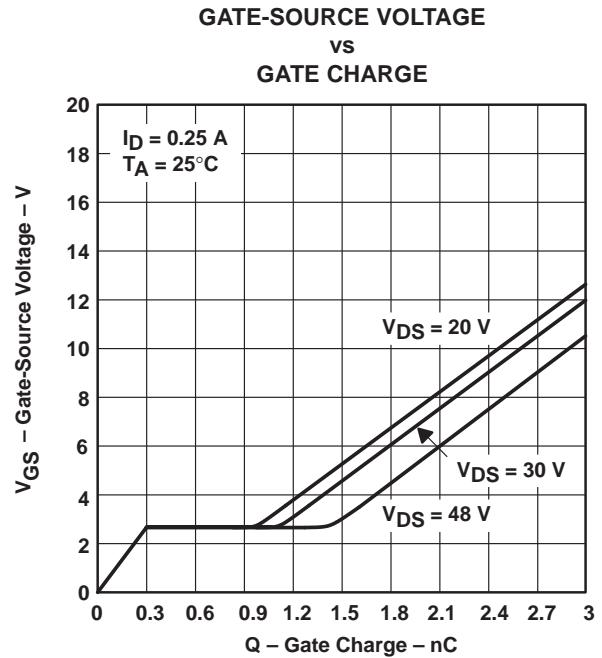


Figure 10

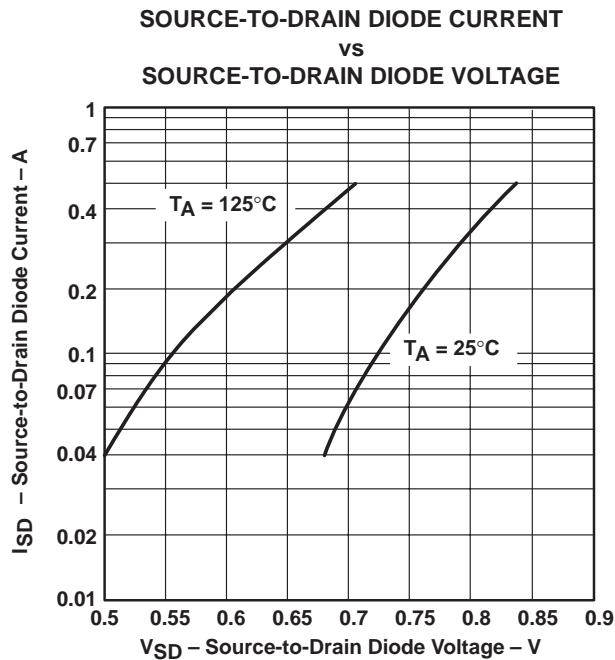


Figure 11

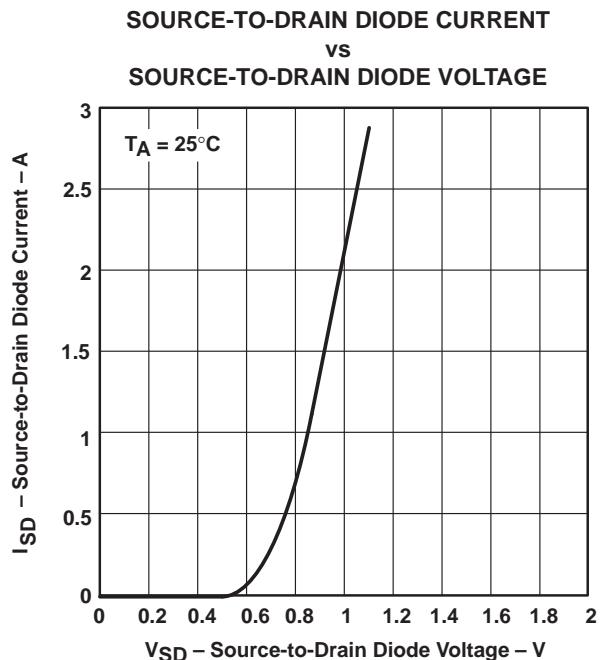


Figure 12

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### TYPICAL CHARACTERISTICS

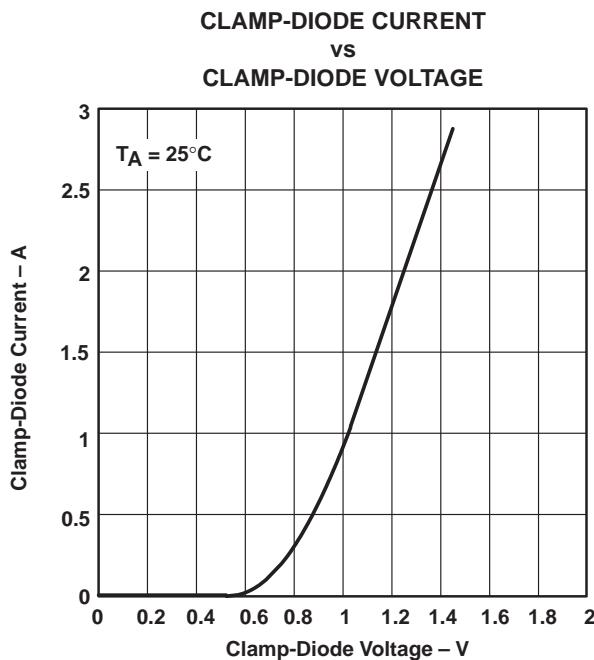


Figure 13

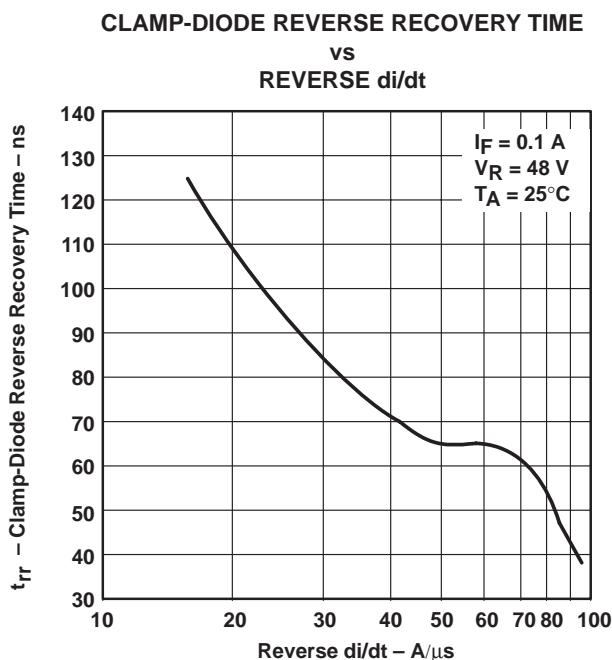
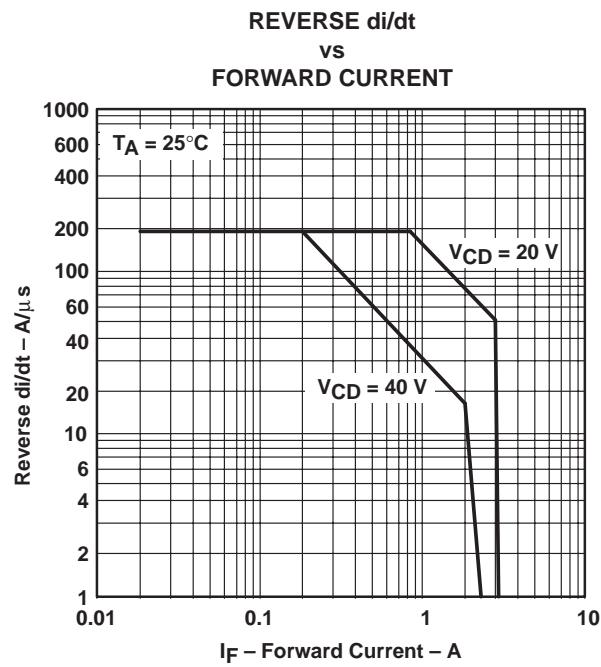


Figure 14



NOTE A:  $V_{CD} = V_{clamp} - V_{drain}$

Figure 15



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**TYPICAL CHARACTERISTICS**

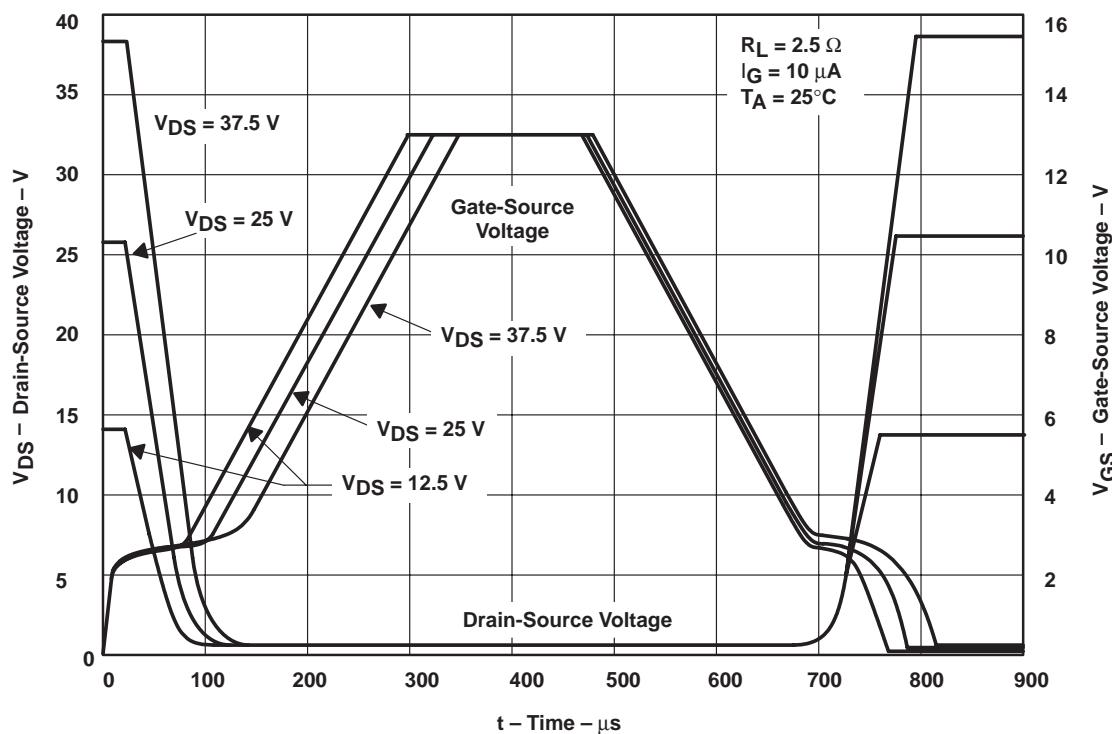


Figure 16. Resistive Switching Waveforms

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### THERMAL INFORMATION

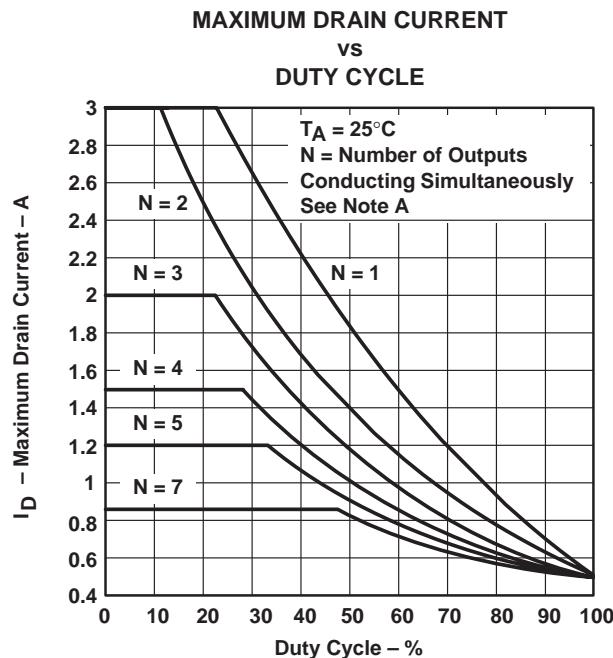


Figure 17

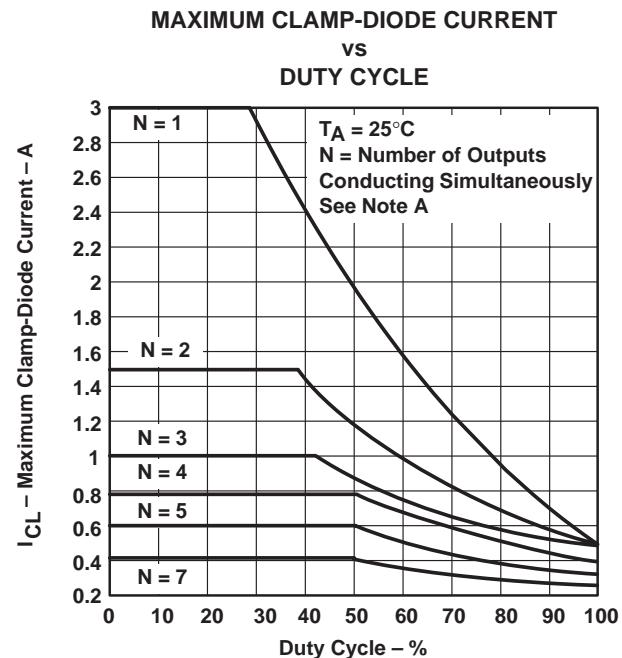
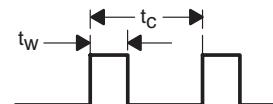


Figure 18



NOTE A: For Figures 17 and 18,  $d = t_W/t_C = 10 \text{ ms} / t_C$ , where  $t_W$  and  $t_C$  are defined by the following:

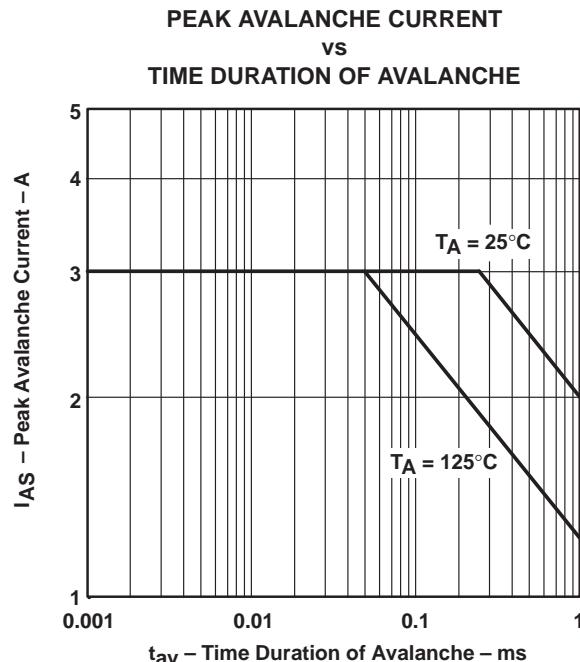


Figure 19

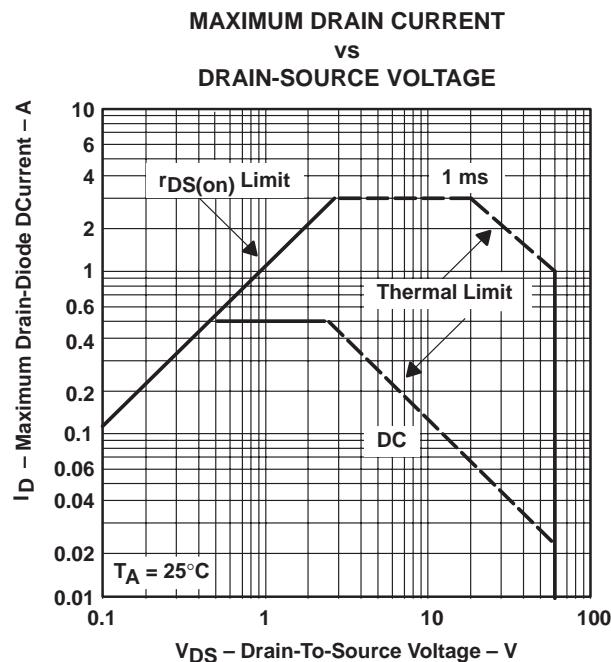
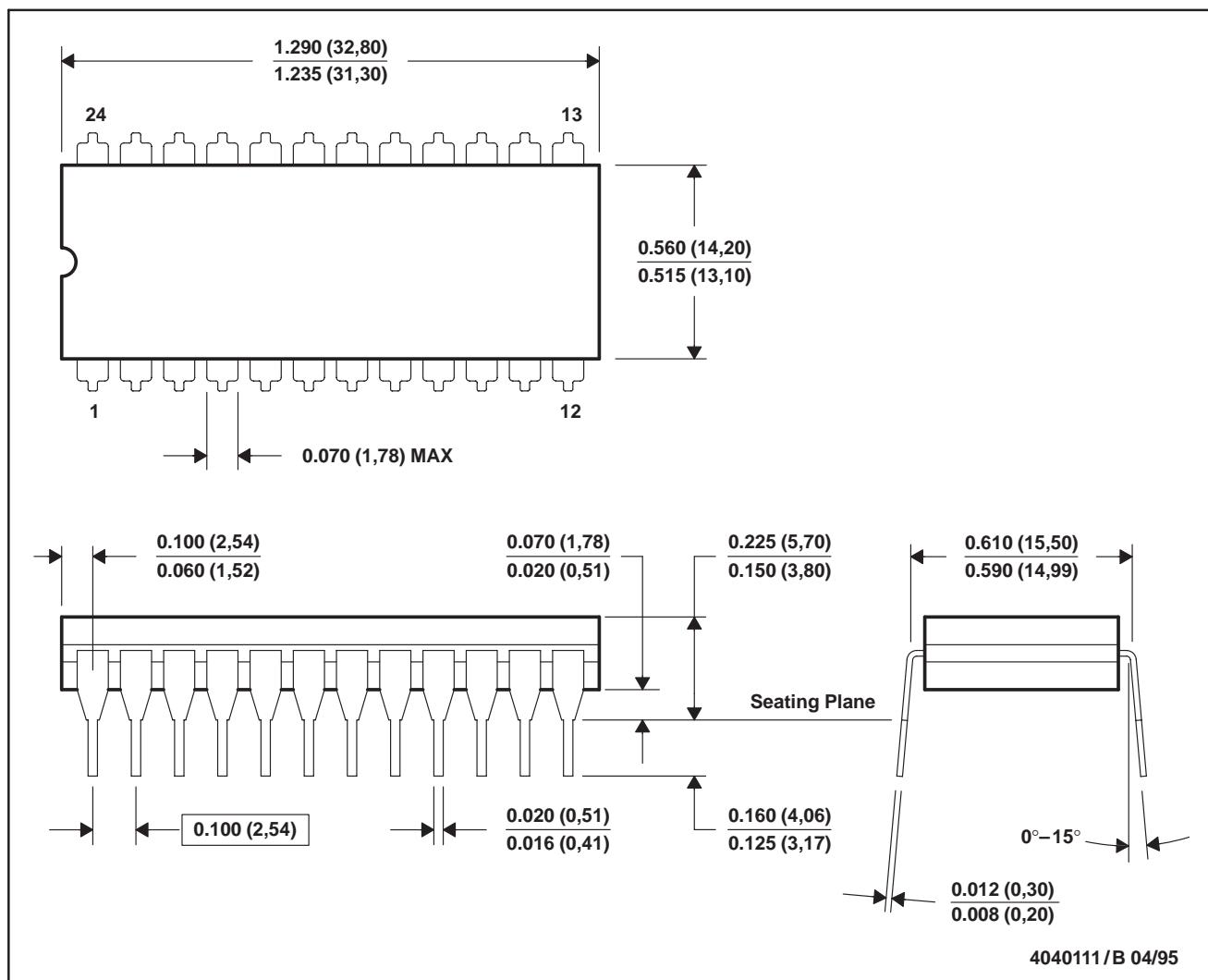


Figure 20

MECHANICAL INFORMATION

JW (R-GDIP-T24)

CERAMIC DUAL-IN-LINE PACKAGE



- NOTES: A. All linear dimensions are in inches (millimeters).  
 B. This drawing is subject to change without notice.  
 C. This package can be hermetically sealed with a ceramic lid using glass frit.  
 D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only  
 E. Falls within MIL-STD-1835 GDIP5-T24

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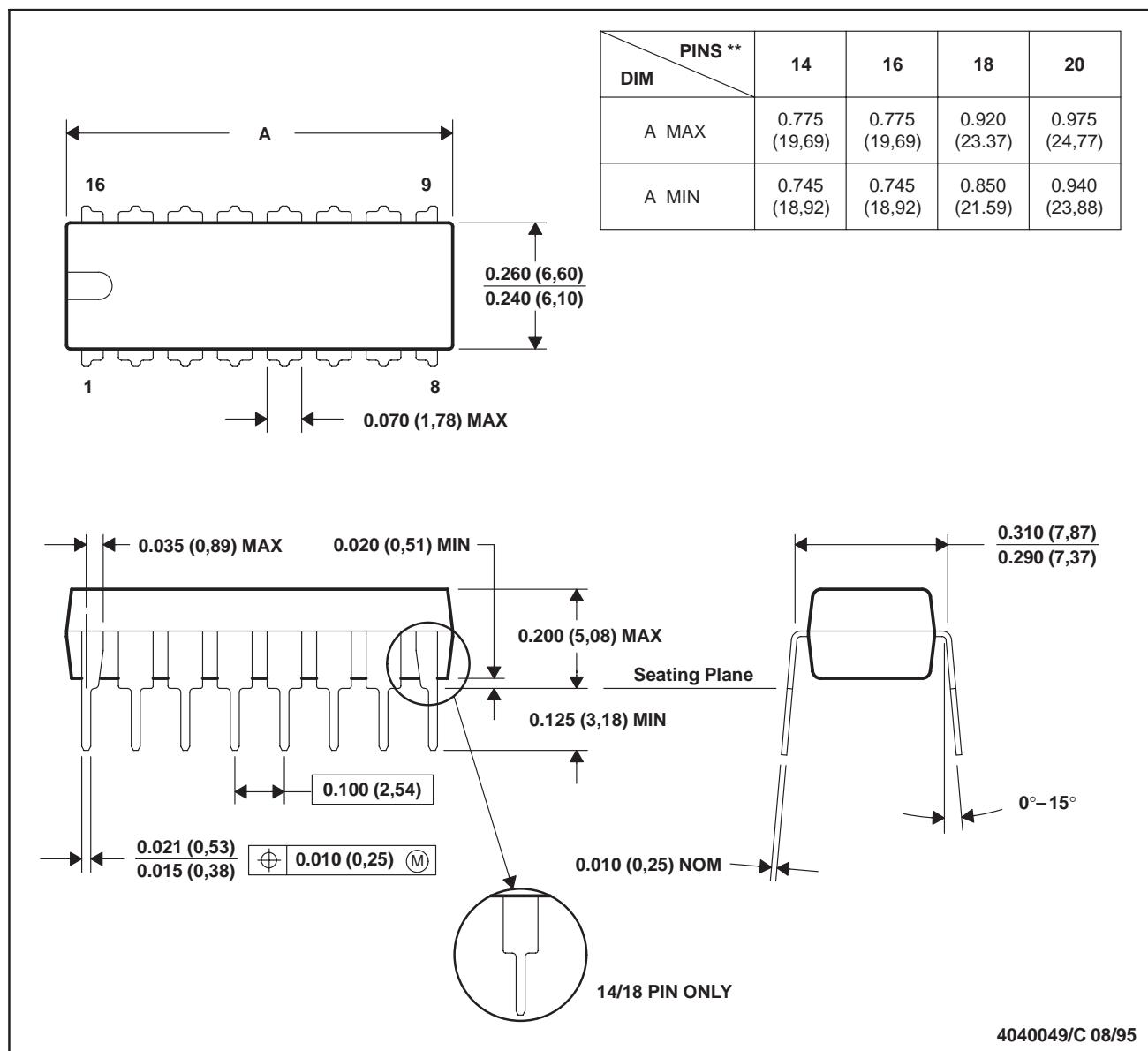
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### MECHANICAL INFORMATION

N (R-PDIP-T\*\*)

16 PIN SHOWN

PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).  
 B. This drawing is subject to change without notice.  
 C. Falls within JEDEC MS-001 (20 pin package is shorter than MS-001.)



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